

Docket No.: MUH-11618

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E. Hillis  
12-5-01



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : UDO HARTMANN  
Filed : Concurrently herewith  
Title : APPARATUS FOR TESTING SEMICONDUCTOR DEVICES

INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner of Patents and Trademarks,  
Washington, D.C. 20231

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:

German Patent DE 38 06 209 C2 (Yamamoto et al.), dated May 14, 1992, pertains to a device for the detection of structural defects of a sample with a regular structure through special filtering of the light diffracted by the sample;

German Translation of the European Patent EP 0 254 691 B1(Cozzi), dated September 23, 1993, pertains to a process and device for testing EPROM-Semiconductors during the burn-in procedure;

German Published, Non-Prosecuted Patent Application DE 39 03 296 A1 (Dakin), dated August 24, 1989, pertains to a scanning set-up usable as a gas probe.

If no translation of pertinent portions of any foreign language patents or publications mentioned above is included with the aforementioned copies of those applications,

patents and/or publications, it is because no existing translation is readily available to the applicant.

Respectfully submitted,



For Applicant

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Date: July 25, 2001

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